

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KAISER ET AL.	
		Examiner	Art Unit	Page 1 of 1
		John P Trimmings	2133	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,337,318	08-1994	Tsukakoshi et al.	714/708
	C	US-5,917,764	06-1999	Ohsawa et al.	365/200
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.